

LOW VOLTAGE CMOS OCTAL D-TYPE LATCH (3-STATE NON INV.) WITH 5V TOLERANT INPUTS

- HIGH SPEED:
 $t_{PD}=6.4ns$ (TYP.) at $V_{CC} = 3.3V$
- 5V TOLERANT INPUTS
- POWER-DOWN PROTECTION ON INPUTS
- INPUT VOLTAGE LEVEL:
 $V_{IL} = 0.8V$, $V_{IH} = 2V$ at $V_{CC} = 3V$
- LOW POWER DISSIPATION:
 $I_{CC} = 4 \mu A$ (MAX.) at $T_A=25^{\circ}C$
- LOW NOISE:
 $V_{OLP} = 0.3V$ (TYP.) at $V_{CC}=3.3V$
- SYMMETRICAL OUTPUT IMPEDANCE:
 $|I_{OH}| = I_{OL} = 4 mA$ (MIN) at $V_{CC} = 3V$
- BALANCED PROPAGATION DELAYS:
 $t_{PLH} \cong t_{PHL}$
- OPERATING VOLTAGE RANGE:
 $V_{CC}(OPR) = 2V$ to $3.6V$ (1.2V Data Retention)
- PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 573
- IMPROVED LATCH-UP IMMUNITY

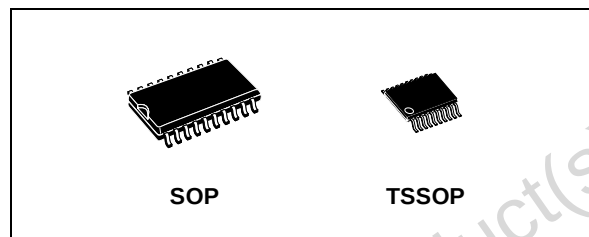


Table 1: Order Codes

PACKAGE	T & R
SOP	74LVX573MTR
TSSOP	74LVX573TTR

When the LE is taken low, the Q outputs will be latched precisely at the logic level of D input data. While the (OE) input is low, the 8 outputs will be in a normal logic state (high or low logic level) and while high level the outputs will be in a high impedance state.

Power down protection is provided on all inputs and 0 to 7V can be accepted on inputs with no regard to the supply voltage.

This device can be used to interface 5V to 3V. It combines high speed performance with the true CMOS low power consumption.

All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

DESCRIPTION

The 74LVX573 is a low voltage CMOS OCTAL D-TYPE LATCH with 3 STATE OUTPUT NON INVERTING fabricated with sub-micron silicon gate and double-layer metal wiring C²MOS technology. It is ideal for low power, battery operated and low noise 3.3V applications.

This 8 bit D-Type latch is controlled by a latch enable input (LE) and an output enable input (OE). While the LE input is held at a high level, the Q outputs will follow the data input precisely.

Figure 1: Pin Connection And IEC Logic Symbols

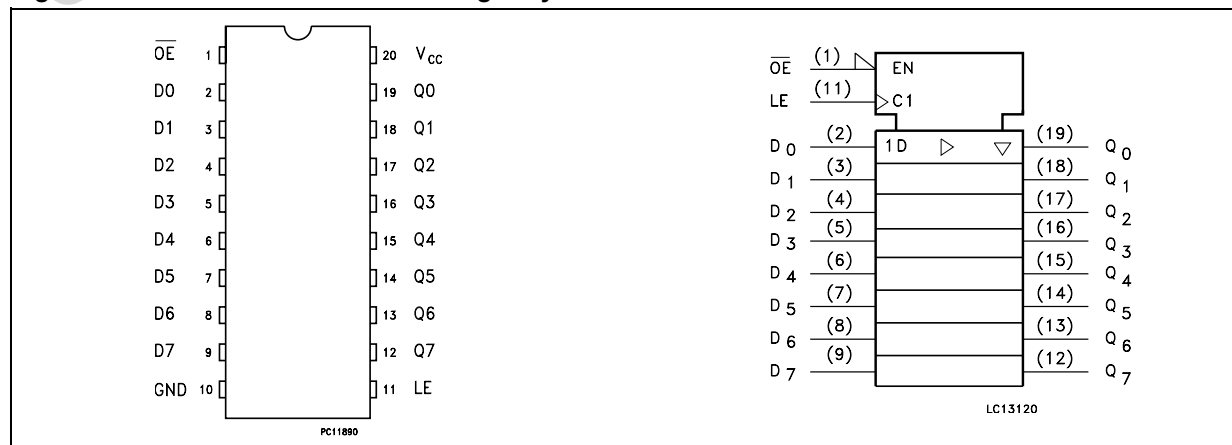


Figure 2: Input Equivalent Circuit

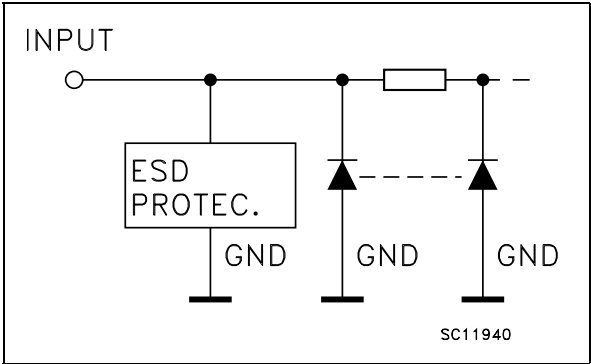


Table 2: Pin Description

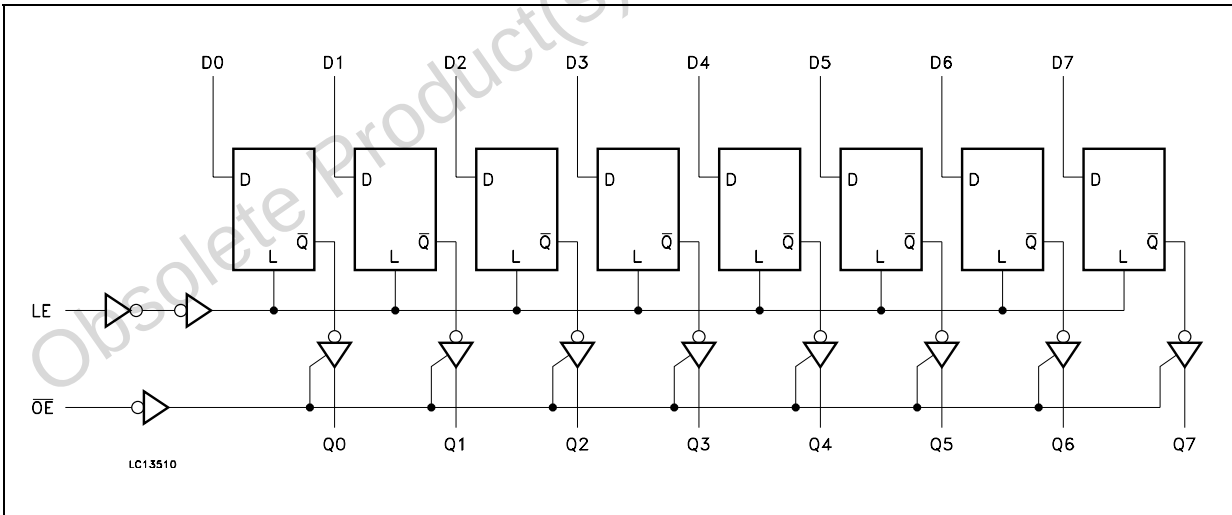
PIN N°	SYMBOL	NAME AND FUNCTION
1	$\overline{OE}$	3 State Output Enable Input (Active LOW)
2, 3, 4, 5, 6, 7, 8, 9	D0 to D7	Data Inputs
12, 13, 14, 15, 16, 17, 18, 19	Q0 to Q7	3-State Latch Outputs
11	LE	Latch Enable Input
10	GND	Ground (0V)
20	V _{CC}	Positive Supply Voltage

Table 3: Truth Table

INPUTS			OUTPUT
$\overline{OE}$	LE	D	Q
H	X	X	Z
L	L	X	NO CHANGE*
L	H	L	L
L	H	H	H

X : Don't Care
Z : High Impedance
* : Q Outputs are Latched at the time when the LE INPUT is taken low logic level

Figure 3: Logic Diagram



This logic diagram has not been used to estimate propagation delays

Table 4: Absolute Maximum Ratings

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	-0.5 to +7.0	V
V_I	DC Input Voltage	-0.5 to +7.0	V
V_O	DC Output Voltage	-0.5 to $V_{CC} + 0.5$	V
I_{IK}	DC Input Diode Current	- 20	mA
I_{OK}	DC Output Diode Current	± 20	mA
I_O	DC Output Current	± 25	mA
I_{CC} or I_{GND}	DC V_{CC} or Ground Current	± 50	mA
T_{stg}	Storage Temperature	-65 to +150	°C
T_L	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied

Table 5: Recommended Operating Conditions

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage (note 1)	2 to 3.6	V
V_I	Input Voltage	0 to 5.5	V
V_O	Output Voltage	0 to V_{CC}	V
T_{op}	Operating Temperature	-55 to 125	°C
dt/dv	Input Rise and Fall Time (note 2) ($V_{CC} = 3V$)	0 to 100	ns/V

1) Truth Table guaranteed: 1.2V to 3.6V

2) V_{IN} from 0.8V to 2.0V

Table 6: DC Specifications

Symbol	Parameter	Test Condition		Value							Unit
		V _{CC} (V)		T _A = 25°C			-40 to 85°C		-55 to 125°C		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
V _{IH}	High Level Input Voltage	2.0		1.5			1.5		1.5		V
		3.0		2.0			2.0		2.0		
		3.6		2.4			2.4		2.4		
V _{IL}	Low Level Input Voltage	2.0				0.5		0.5		0.5	V
		3.0				0.8		0.8		0.8	
		3.6				0.8		0.8		0.8	
V _{OH}	High Level Output Voltage	2.0	I _O =-50 μA	1.9	2.0		1.9		1.9		V
		3.0	I _O =-50 μA	2.9	3.0		2.9		2.9		
		3.0	I _O =-4 mA	2.58			2.48		2.4		
V _{OL}	Low Level Output Voltage	2.0	I _O =50 μA		0.0	0.1		0.1		0.1	V
		3.0	I _O =50 μA		0.0	0.1		0.1		0.1	
		3.0	I _O =4 mA			0.36		0.44		0.55	
I _{OZ}	High Impedance Output Leakage Current	3.6	V _I = V _{IH} or V _{IL} V _O = V _{CC} or GND			±0.25		± 2.5		± 2.5	μA
I _I	Input Leakage Current	3.6	V _I = 5V or GND			± 0.1		± 1		± 1	μA
I _{CC}	Quiescent Supply Current	3.6	V _I = V _{CC} or GND			4		40		40	μA

Table 7: Dynamic Switching Characteristics

Symbol	Parameter	Test Condition		Value						Unit	
		V _{CC} (V)		T _A = 25°C			-40 to 85°C		-55 to 125°C		
				Min.	Typ.	Max.	Min.	Max.	Min.		Max.
V _{OLP}	Dynamic Low Voltage Quiet	3.3	C _L = 50 pF		0.3	0.8					V
V _{OLV}	Output (note 1, 2)			-0.8	-0.3						
V _{IHD}	Dynamic High Voltage Input (note 1, 3)	3.3		2.0							
V _{ILD}	Dynamic Low Voltage Input (note 1, 3)	3.3				0.8					

1) Worst case package.

2) Max number of outputs defined as (n). Data inputs are driven 0V to 3.3V, (n-1) outputs switching and one output at GND.

3) Max number of data inputs (n) switching. (n-1) switching 0V to 3.3V. Inputs under test switching: 3.3V to threshold (V_{ILD}), 0V to threshold (V_{IHD}), f=1MHz.Table 8: AC Electrical Characteristics (Input t_r = t_f = 3ns)

Symbol	Parameter	Test Condition			Value						Unit	
		V _{CC} (V)	C _L (pF)		T _A = 25°C			-40 to 85°C		-55 to 125°C		
					Min.	Typ.	Max.	Min.	Max.	Min.		Max.
t _{PLH} t _{PHL}	Propagation Delay Time LE to Q	2.7	15			8.2	15.6	1.0	18.5	1.0	18.5	ns
		2.7	50			10.7	19.1	1.0	22.0	1.0	22.0	
		3.3(*)	15			6.4	10.1	1.0	12.0	1.0	12.0	
		3.3(*)	50			8.9	13.6	1.0	15.5	1.0	15.5	
t _{PLH} t _{PHL}	Propagation Delay Time D to Q	2.7	15			7.6	14.5	1.0	17.5	1.0	17.5	ns
		2.7	50			10.1	18.0	1.0	21.0	1.0	21.0	
		3.3(*)	15			5.9	9.3	1.0	11.0	1.0	11.0	
		3.3(*)	50			8.4	12.8	1.0	14.5	1.0	14.5	
t _{PZL} t _{PZH}	Output Enable Time	2.7	15			7.8	15.0	1.0	18.5	1.0	18.5	ns
		2.7	50			10.3	18.5	1.0	22.0	1.0	22.0	
		3.3(*)	15			6.1	9.7	1.0	12.0	1.0	12.0	
		3.3(*)	50			8.6	13.2	1.0	15.5	1.0	15.5	
t _{PLZ} t _{PHZ}	Output Disable Time	2.7	50			12.1	19.1	1.0	22.0	1.0	22.0	ns
		3.3(*)	50			10.1	13.6	1.0	15.5	1.0	15.5	
t _W	LE pulse Width, HIGH	2.7	50				6.5		7.5		7.5	ns
		3.3(*)	50				5.0		5.0		5.0	
t _S	Setup Time D to LE HIGH or LOW	2.7	50				5.0		5.0		5.0	ns
		3.3(*)	50				3.5		3.5		3.5	
t _h	Hold Time D to LE HIGH or LOW	2.7	50				1.5		1.5		1.5	ns
		3.3(*)	50				1.5		1.5		1.5	
t _{OSLH} t _{OSHL}	Output to Output Skew Time (note 1,2)	2.7	50			0.5	1.0		1.5		1.5	ns
		3.3(*)	50			0.5	1.0		1.5		1.5	

1) Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs of the same device switching in the same direction, either HIGH or LOW

2) Parameter guaranteed by design

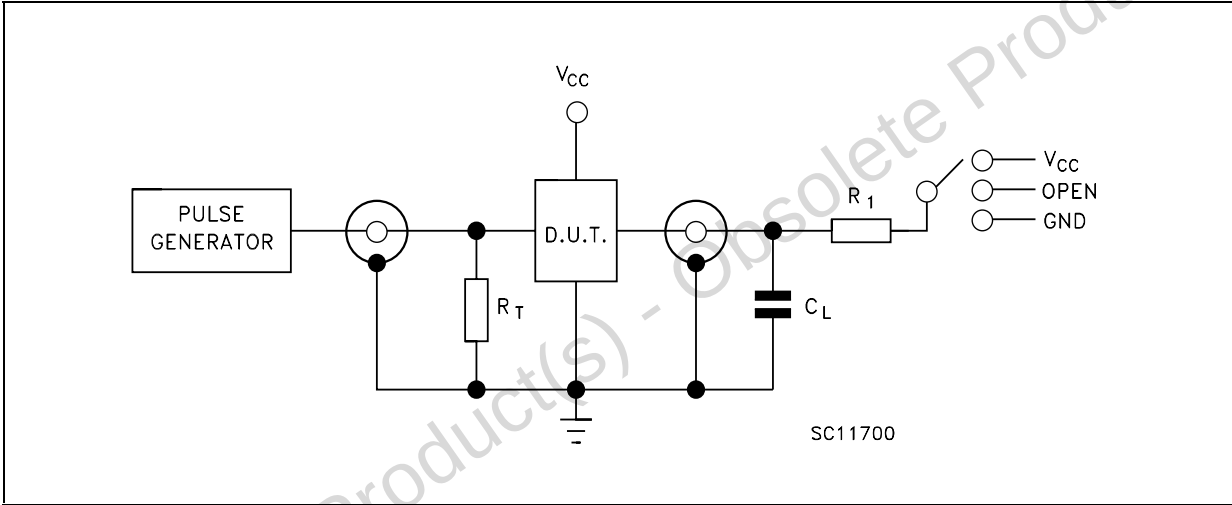
(*) Voltage range is 3.3V ± 0.3V

Table 9: Capacitive Characteristics

Symbol	Parameter	Test Condition		Value						Unit	
		V _{CC} (V)		T _A = 25°C			-40 to 85°C		-55 to 125°C		
				Min.	Typ.	Max.	Min.	Max.	Min.		Max.
C _{IN}	Input Capacitance	3.3			4	10		10		10	pF
C _{OUT}	Output Capacitance	3.3			6						pF
C _{PD}	Power Dissipation Capacitance (note 1)	3.3	f _{IN} = 10MHz		29						pF

1) C_{PD} is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation. I_{CC(OPR)} = C_{PD} × V_{CC} × f_{IN} + I_{CC}/8 (per circuit)

Figure 4: Test Circuit



TEST	SWITCH
t _{PLH} , t _{PHL}	Open
t _{PZL} , t _{PLZ}	V _{CC}
t _{PZH} , t _{PHZ}	GND

C_L = 15/50pF or equivalent (includes jig and probe capacitance)
R_L = R₁ = 1KΩ or equivalent
R_T = Z_{OUT} of pulse generator (typically 50Ω)

Figure 5: Waveform - LE To Qn Propagation Delays, Le Minimun Pulse Width, Dn To LE Setup And Hold Times (f=1MHz; 50% duty cycle)

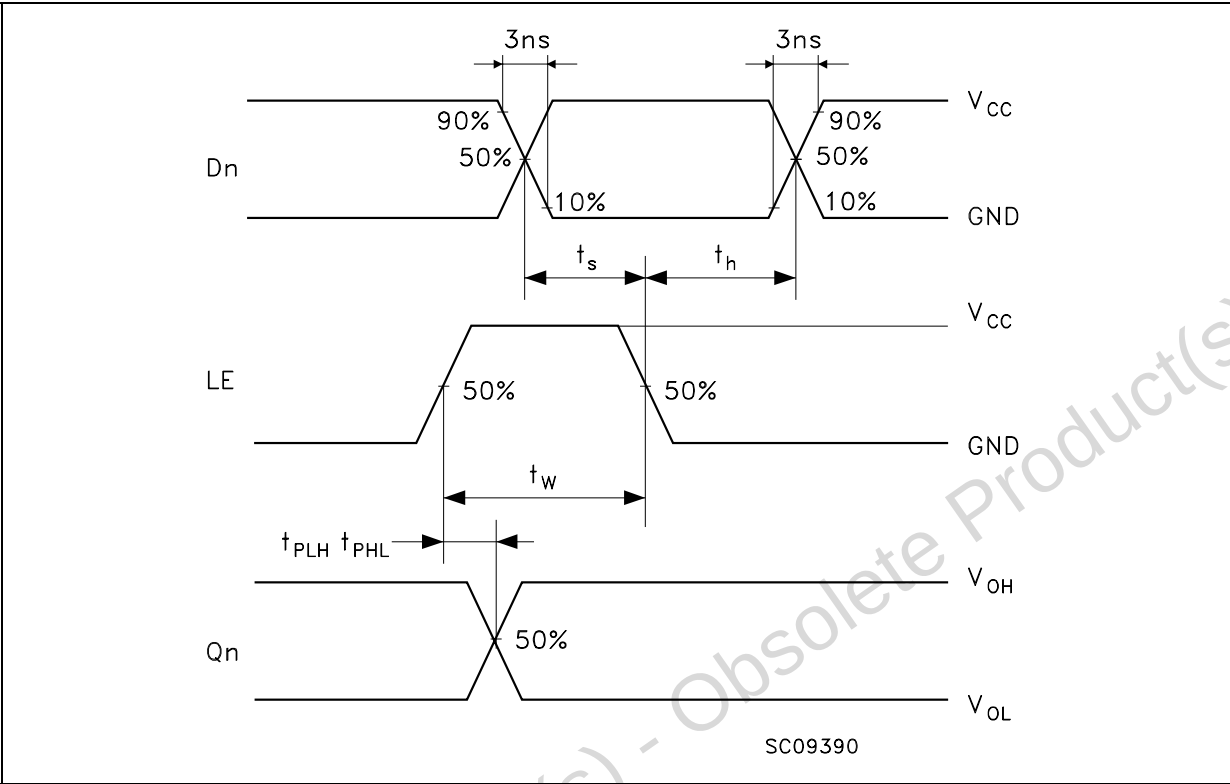


Figure 6: Waveform - Output Enable And Disable Times (f=1MHz; 50% duty cycle)

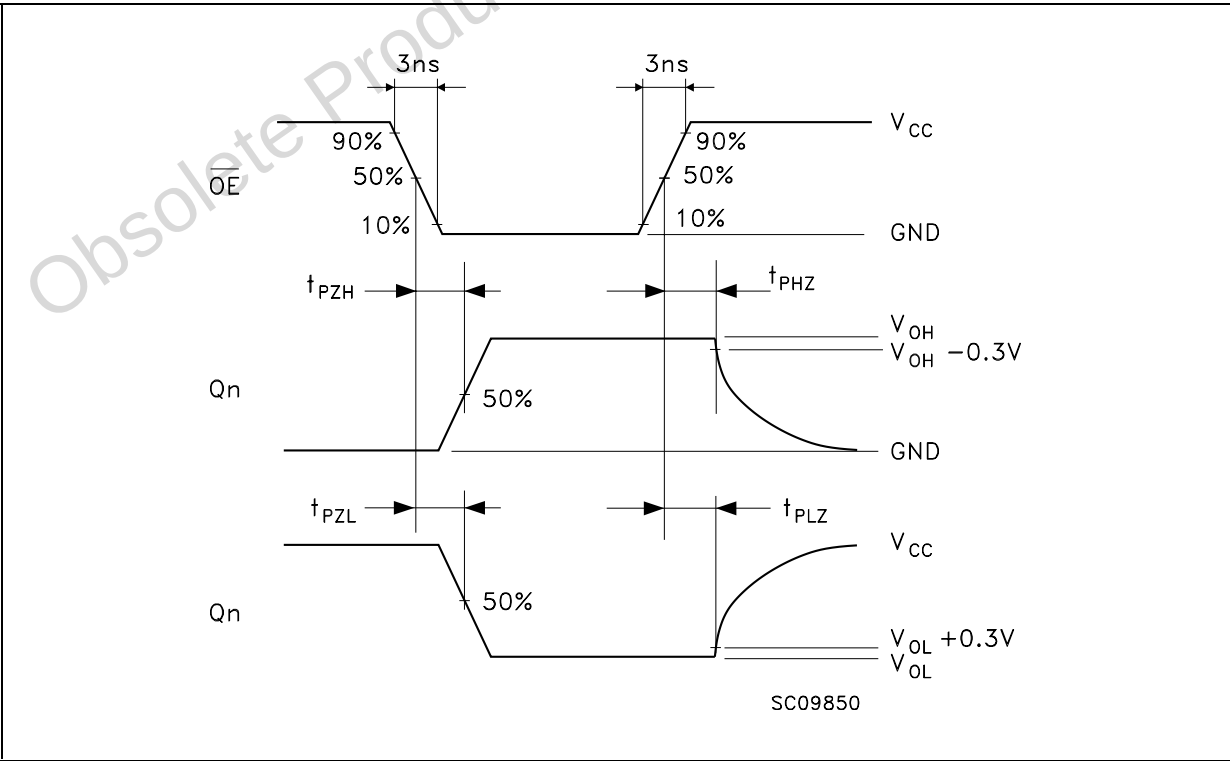
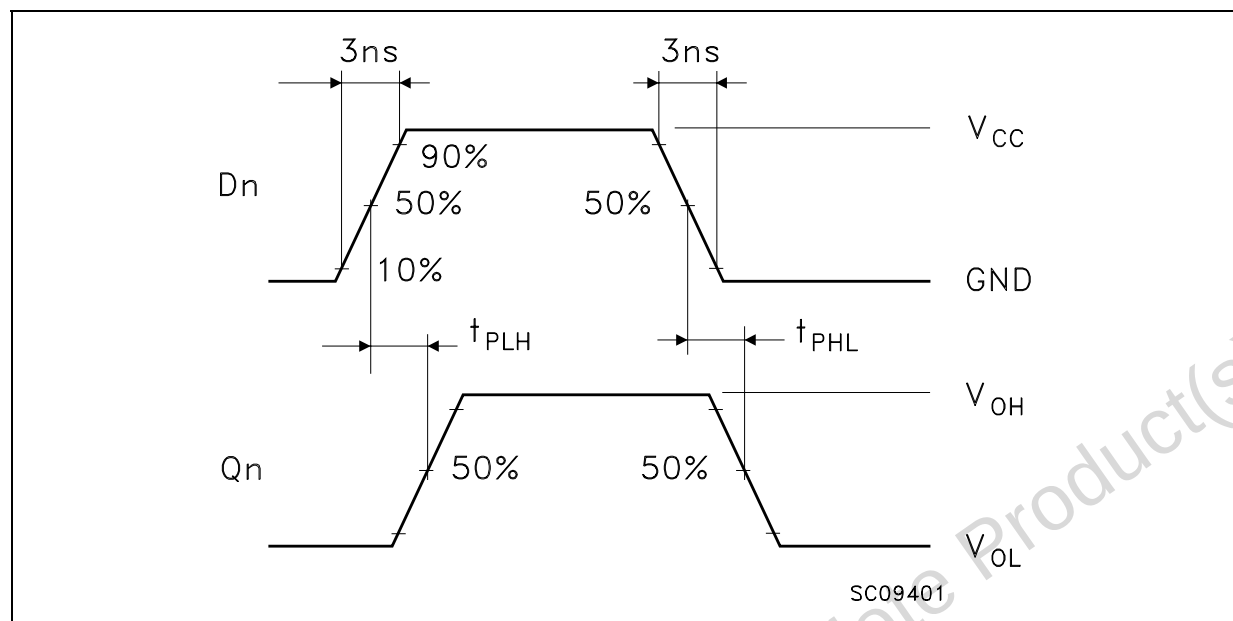
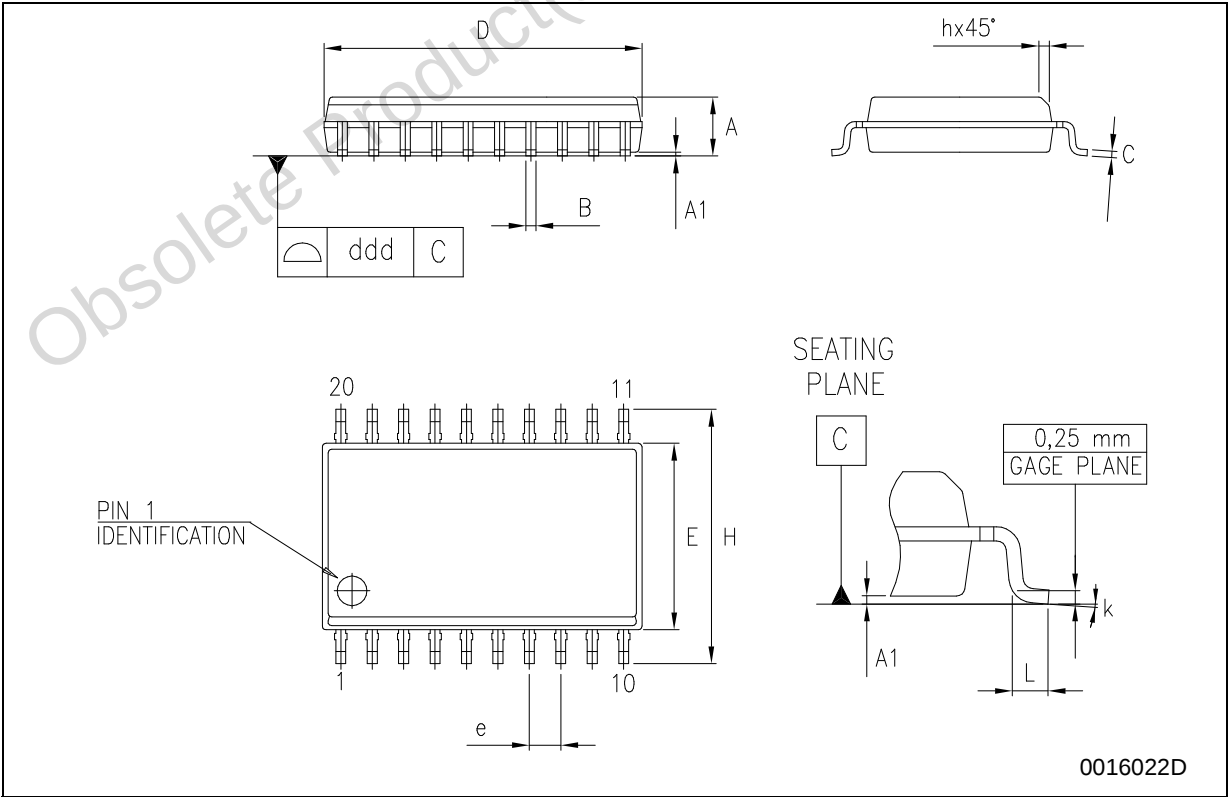


Figure 7: Waveform - Propagation Delay Time ($f=1\text{MHz}$; 50% duty cycle)

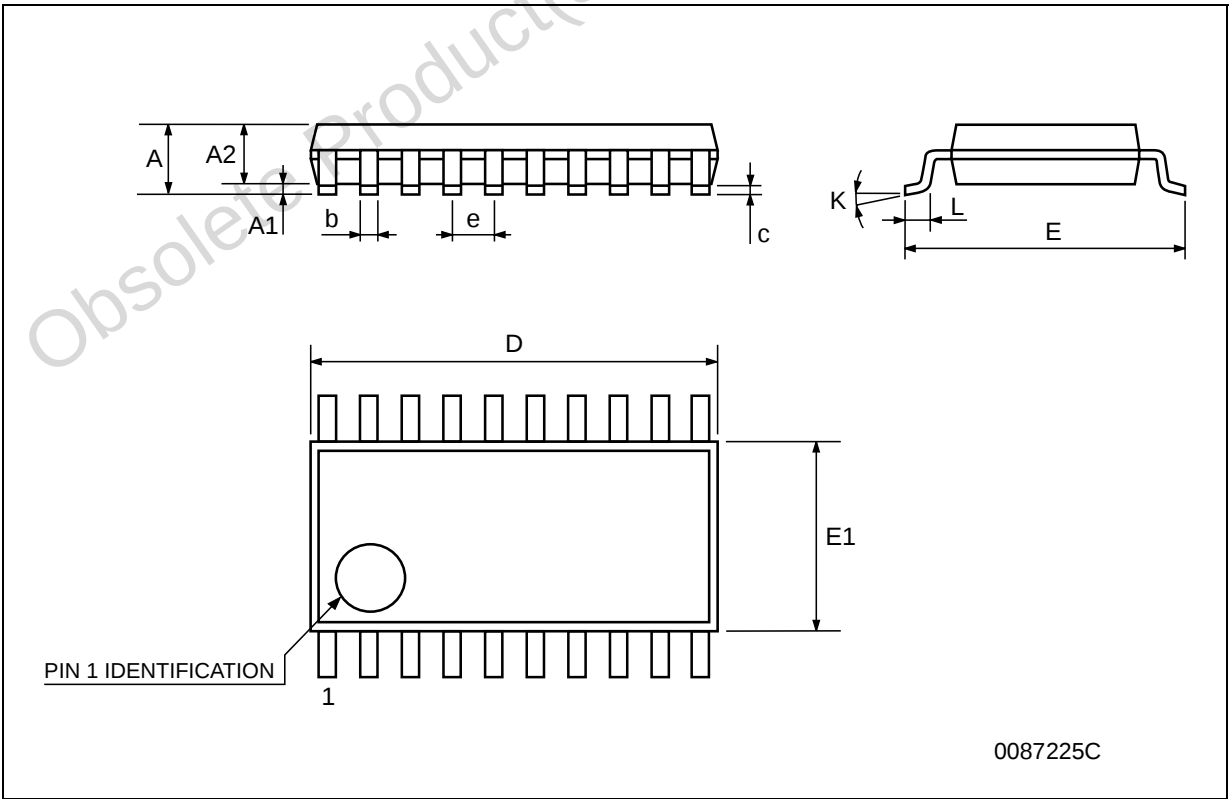
SO-20 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A	2.35		2.65	0.093		0.104
A1	0.1		0.30	0.004		0.012
B	0.33		0.51	0.013		0.020
C	0.23		0.32	0.009		0.013
D	12.60		13.00	0.496		0.512
E	7.4		7.6	0.291		0.299
e		1.27			0.050	
H	10.00		10.65	0.394		0.419
h	0.25		0.75	0.010		0.030
L	0.4		1.27	0.016		0.050
k	0°		8°	0°		8°
ddd			0.100			0.004



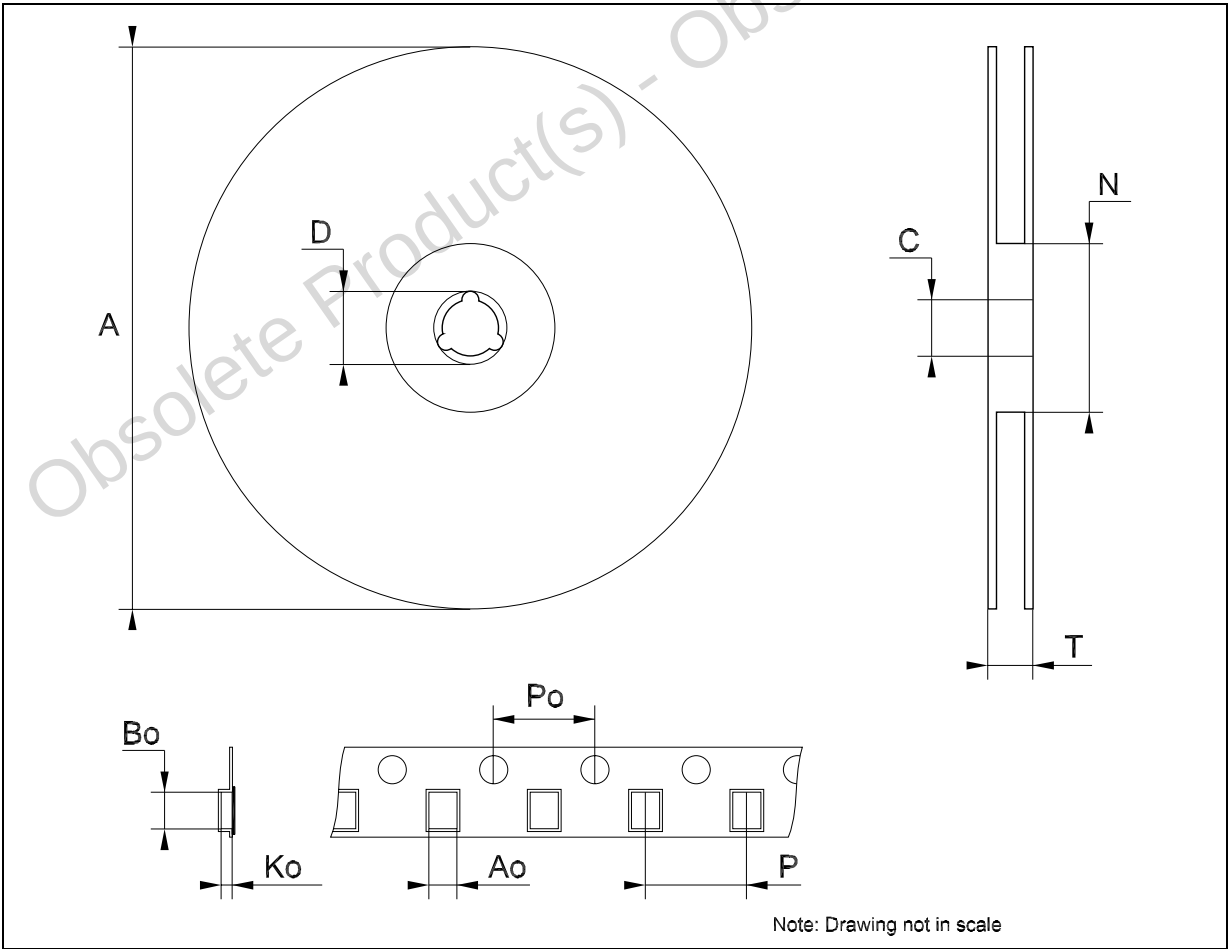
TSSOP20 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A			1.2			0.047
A1	0.05		0.15	0.002	0.004	0.006
A2	0.8	1	1.05	0.031	0.039	0.041
b	0.19		0.30	0.007		0.012
c	0.09		0.20	0.004		0.0079
D	6.4	6.5	6.6	0.252	0.256	0.260
E	6.2	6.4	6.6	0.244	0.252	0.260
E1	4.3	4.4	4.48	0.169	0.173	0.176
e		0.65 BSC			0.0256 BSC	
K	0°		8°	0°		8°
L	0.45	0.60	0.75	0.018	0.024	0.030



Tape & Reel SO-20 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A			330			12.992
C	12.8		13.2	0.504		0.519
D	20.2			0.795		
N	60			2.362		
T			30.4			1.197
Ao	10.8		11	0.425		0.433
Bo	13.2		13.4	0.520		0.528
Ko	3.1		3.3	0.122		0.130
Po	3.9		4.1	0.153		0.161
P	11.9		12.1	0.468		0.476



Tape & Reel TSSOP20 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A			330			12.992
C	12.8		13.2	0.504		0.519
D	20.2			0.795		
N	60			2.362		
T			22.4			0.882
Ao	6.8		7	0.268		0.276
Bo	6.9		7.1	0.272		0.280
Ko	1.7		1.9	0.067		0.075
Po	3.9		4.1	0.153		0.161
P	11.9		12.1	0.468		0.476

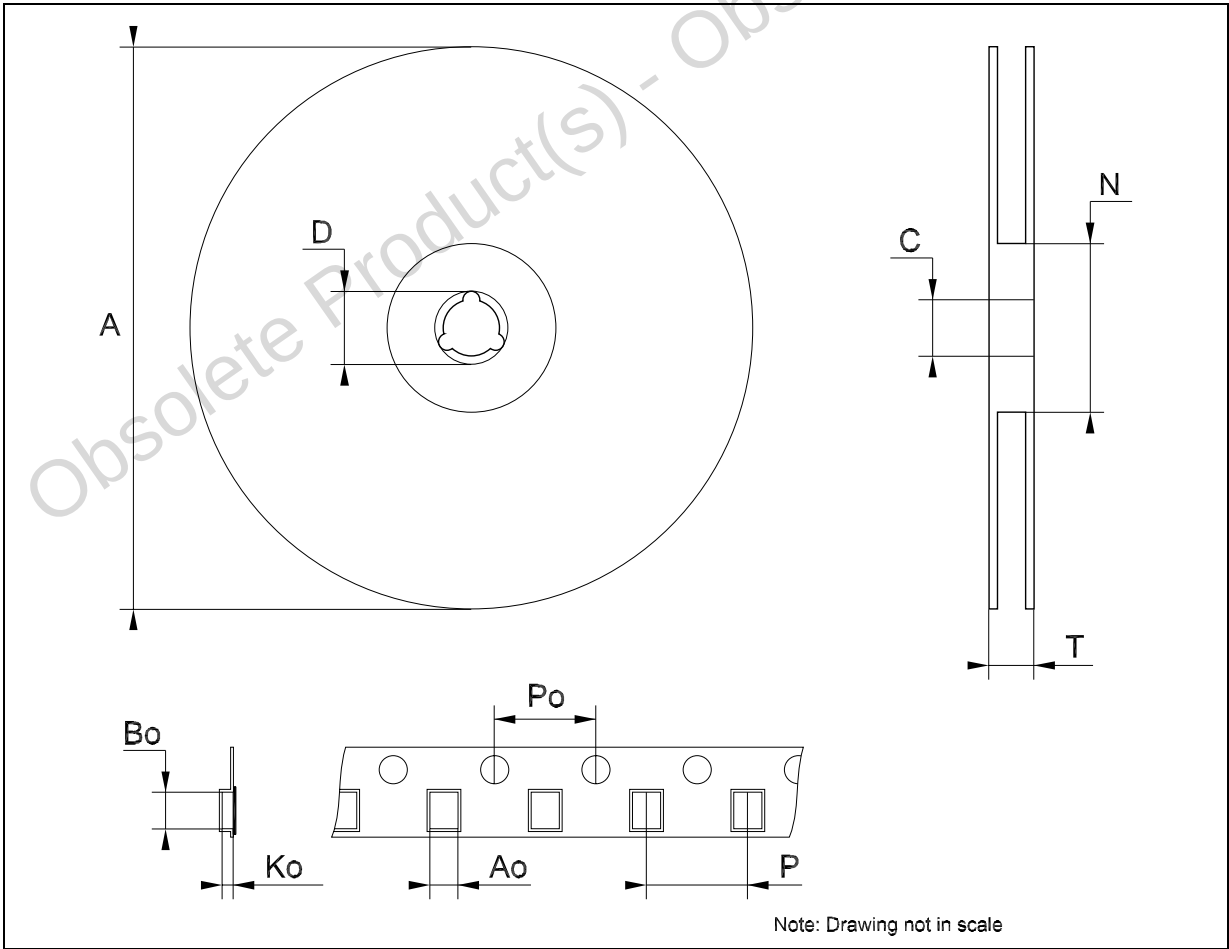


Table 10: Revision History

Date	Revision	Description of Changes
27-Aug-2004	4	Ordering Codes Revision - pag. 1.

Obsolete Product(s) - Obsolete Product(s)

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